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2. “Enhanced characterization of electrical connection degradation”.
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29. “Critical temperature of low-dimensional high- T_C superconductors”,
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CONFERENCE PRESENTATIONS

1. Tech-Talk, September 28, 2006, Sun Microsystems, Sunnyvale, CA
“Reliability Evaluation of Critical Component Inside the IO Box of Next Generation Enterprise-Class Sun Servers”
2. International Symposium for Testing and Failure Analysis, November 6-10, 2005, San Jose, CA
“Physics of failure investigation of dark VCSELs: Detection of reverse-bias electroluminescence by photo-emission microscopy”
3. International Symposium for Testing and Failure Analysis, November 14-18, 2004, Worcester, MA
“Characterization of VCSEL-array Degradation Induced by Elevated Temperature and Humidity”
4. Physical Sciences Center Technical Seminar, Sun Microsystems, April 15, 2004, San Diego, CA
“VCSEL reliability study at PSC of SMI in San Diego”
5. International Symposium on Optical Science, Engineering, and Instrumentation, SPIE’s Annual Meeting, 4-9 August 1996, Denver, CO
“Dynamics of Photoexcitations in fullerene-doped conjugated polymers”
6. International Conference on Science and Technology of Synthetic Metals, ICSM 1996, July 28-August 2, 1996, Snowbird, UT
“Electroluminescence from Poly(Phenylene Vinylene) in a Planar Metal-Polymer-Metal Structure”
7. CPIMA Forum on Display Materials, July 29-30, 1996, Stanford University, Palo Alto, CA
“Electroluminescence from poly(phenylene vinylene) and its derivatives in a planar metal-polymer-metal structure”
8. The 1993 March Meeting of the American Physical Society, 22-26 March 1993, Seattle, WA
“New bond orientated auxiliary particle methods for t-J model”
9. Seminars of the Physics Department on High-TC Superconductors, February 1989, Cluj Napoca, Romania
“A plasmonic mechanism for High-Tc”